Giant piezoelectricity of monolayer group IV monochalcogenides: SnSe, SnS, GeSe, and GeS

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We predict enormous, anisotropic piezoelectric effects in intrinsic monolayer group IV monochalcogenides (MX, M=Sn or Ge, X=Se or S), including SnSe, SnS, GeSe, and GeS. Using first-principle simulations based on the modern theory of polarization, we find that their piezoelectric coefficients are about one to two orders of magnitude larger than those of other 2D materials, such as MoS2 and GaSe, and bulk quartz and AlN which are widely used in industry. This enhancement is a result of the unique “puckered” C2v symmetry and electronic structure of monolayer group IV monochalcogenides. Given the achieved experimental advances in the fabrication of monolayers, their flexible character, and ability to withstand enormous strain, these 2D structures with giant piezoelectric effects may be promising for a broad range of applications such as nano-sized sensors, piezotronics, and energy harvesting in portable electronic devices. © 2015 AIP Publishing LLC.

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Piezoelectric materials, which convert mechanical energy to electrical energy, have the advantages of large power densities and ease of application in sensors and energy harvesting.1,2 For example, a widely used piezoelectric material is lead zirconate titanate Pb(ZrxTi1−x)O3, a piezoceramic known as PZT.3−5 However, the piezoceramic’s brittle nature causes limitations in the sustainable strain.6 Meanwhile, non-centrosymmetric wurtzite-structured semiconductors, such as ZnO, GaN, and InN, are wildly used in the piezotronic and piezophototronic devices.7,8 In particular, their nanowires or nanobelts10−12 are expected to be useful for electromechanical coupled sensors, nanoscale energy conversion.10−13 However, the much smaller piezoelectric coefficients of wurtzite semiconductors limit the mechanical-electrical energy conversion efficiency.7,8

Recently, two-dimensional (2D) materials have sparked interest for the piezoelectric applications because of their high crystallinity and ability to withstand enormous strain. For those hexagonal structures with a D6h point group, such as boron nitride (h-BN) and many transition-metal dichalcogenides (TMDCs), as well as layered orthorhombic structure with a D4h point group, such as group-III monochalcogenides, their atomic structure is presented in Figs. 1(c) and 1(d), which exhibit a C2v point group. Their puckered C2v symmetries are much more flexible (softer) along the armchair direction. This can further enhance the piezoelectric. (3) Significant advances in fabrication techniques have been achieved. For example, few-layer SnSe has been fabricated recently.25

In this letter, we employ the first-principles density functional theory (DFT) simulations to calculate the piezoelectric effects of monolayer group IV monochalcogenides. The piezoelectric effect of these monolayer materials is dramatically enhanced and anisotropic, and the most important piezoelectric coefficient d11 is about two orders of magnitude larger than that of 2D and bulk materials,7,14,16 which have been widely used in the industry. These anisotropic, giant piezoelectric materials represent a new class of nanomaterials that will allow for the next generation of ultra-sensitive mechanical detectors, energy conversion devices, and consumer-touch sensors.

The DFT calculations with the Perdew-Burke-Ernzerh (PBE) functional26 have been carried out by using the Vienna Ab initio Simulation Package (VASP) with a plane wave basis set.27,28 and the projector-augmented wave method.29 The Brillouin zone integration is obtained by a 14 × 14 × 1 k-point grid. The convergence criteria for electronic and ionic relaxations are 10−6 eV and 10−5 eV/Å, respectively. We use the “Berry-phase” theory of polarization to directly compute the electric polarization.30−32 The change of polarization (ΔP)
The DFT-optimized monolayer and bulk structure parameters, i.e., the in-plane lattice constants \(a\) and \(b\), are listed in Table I. The corresponding experimental or the previous DFT results of the bulk phase are listed as well.\(^{33–42}\) We observe a similar trend as that in Ref.\(^{42}\), in which the lattice constant \(a\) increases and the constant \(b\) decreases with increasing the number of layers for most group IV monochalcogenides, except for GeS. These monolayers are metastable. This is evidenced by recent experimental fabrications\(^{25}\) and theoretical phonon calculations.\(^{43}\)

We have calculated the electronic structure of group IV monochalcogenides in the supplementary material.\(^{44}\) All these materials exhibit an indirect band gap at the DFT level. We observe a number of layers for most group IV monochalcogenides, and the constant \(b\) decreases with increasing the number of layers for most group IV monochalcogenides, except for GeS. These monolayers are metastable. This is evidenced by recent experimental fabrications\(^{25}\) and theoretical phonon calculations.\(^{43}\)

Fortunately, piezoelectric properties are ground-state properties and the DFT calculation is a suitable tool shown to reliably predict the values. For example, the DFT-calculated piezoelectric coefficients are in excellent agreement with the experimental values for the bulk GaN.\(^{48}\) Very recently, experiments measured the piezoelectric coefficient \(e_{11} = 2.9 \times 10^{-10} \text{ C/m}\) for monolayer MoSe\(_2\), which is close to the DFT results \((3.6 \times 10^{-10} \text{ C/m})\).\(^{14,23}\) Therefore, we employ the same theoretical approach in this work.

We first obtained the planar elastic stiffness coefficients \(C_{11}, C_{22},\) and \(C_{12}\) of the MX monolayer by fitting the DFT-calculated unit-cell energy \(U\) to a series of 2D strain states \((\varepsilon_{11},\varepsilon_{22})\), based on the formula

\[
C_{11} = \frac{1}{A_0} \frac{\partial^2 U}{\partial \varepsilon_{11}^2}, \quad C_{22} = \frac{1}{A_0} \frac{\partial^2 U}{\partial \varepsilon_{22}^2}, \quad C_{12} = \frac{1}{A_0} \frac{\partial^2 U}{\partial \varepsilon_{11} \partial \varepsilon_{22}},
\]

where \(A_0\) is the unit-cell area at the zero strain. Due to the existence of mirror symmetry along the zigzag direction \((y\) direction), at the small strain limit, we can write

\[
\Delta U(\varepsilon_{11}, \varepsilon_{22}) = \frac{1}{2} C_{11} \varepsilon_{11}^2 + \frac{1}{2} C_{22} \varepsilon_{22}^2 + C_{12} \varepsilon_{11} \varepsilon_{22},
\]

where \(\Delta U(\varepsilon_{11}, \varepsilon_{22}) = [U(\varepsilon_{11}, \varepsilon_{22}) - U(\varepsilon_{11} = 0, \varepsilon_{22} = 0)]/A_0\) is the change of unit-cell energy per area. We carry out the strain energy calculation on an \(11 \times 11\) grid with \(\varepsilon_{11}\) and \(\varepsilon_{22}\) ranging from \(-0.005\) to \(0.005\). The atomic positions in the strained unit cell are allowed to be fully relaxed. Following the definitions of previous works,\(^{24}\) the coefficients \(C_{11}, C_{22},\) and \(C_{12}\), which are calculated using a fully relaxed atomic configuration, are called relaxed-ion stiffness coefficients, which are experimentally relevant. In contrast, if the atomic positions are held when applying strain, the so-called clamped-ion coefficients, which represent the piezoelectric effect from the electronic contribution,\(^{29}\) can be calculated as well.

Table II summarizes the clamped and relaxed-ion stiffness coefficients for the four types of \(C_{2v}\) symmetry MX.
monolayers. Additionally, we have also listed the elastic stiffness of another two typical D3h symmetry piezoelectric materials, MoS2 and GaSe. According to the structures shown in Figs. 1(c) and 1(d), group IV monochalcogenides are soft along the armchair (x) direction. This is consistent with our DFT results in Table II. In particular, for both clamped and relax-ion cases, the elastic stiffnesses (C11) of group-IV monochalcogenides are about 4–6 times smaller than that of MoS2 and GaSe. This will significantly enhance the piezoelectric effects. An unexpected result from Table II is that the elastic stiffness (C22) along the zigzag (y) direction is also substantially smaller (around 2–3 times) than that of MoS2 and GaSe. This may be attributed to the intrinsic electronic properties of group IV monochalcogenides, whose covalence bonds are weaker than those of hexagonal TMDCs and group III monochalcogenides. This is also reflected in their longer bond lengths (2.50–2.89 Å), compared with those of GaSe (2.47 Å) and MoS2 (1.84 Å).4,16

Recently, puckered 2D structures, such as few-layer black phosphorus (phosphorene) and similar isoelectronic materials have attracted significant research interests. Due to their novel structure, phosphorene exhibits an unusually negative Poisson ratio.51 Here, we have calculated the Poisson ratio ν⊥ obtained directly from relaxed ion coordinates by evaluating the change of layer thickness in response to in-plane hydrostatic strain Δh/h = −ν⊥(ε11 + ε22). The Poisson ratio ν⊥ is investigated by averaging the results of the armchair direction and zigzag direction for small stress (~0.8%–0.8%). Interestingly, our calculated value is positive and similar to those of the TMDCs and group III monochalcogenides. This differs from the result of phosphorene, in which the Poisson ratio is evaluated by the value only from the armchair direction within a much larger stress range (~5%–5%).51

Next, we calculated the linear piezoelectric coefficients of the group IV MX monolayers by evaluating the change of unit-cell polarization after imposing uniaxial strain. The linear piezoelectric coefficients εijk and dijk are third-rank tensors as they relate polarization vector P, to strain εijk and stress σijk, respectively,

\[ ε_{ijk} = \frac{∂P_j}{∂σ_{ijk}}, \]

Because of the mirror symmetry along the zigzag (y) direction, the independent piezoelectric coefficients are \{ε111, ε122, ε212 = ε221\} and \{d111, d122, d212 = d221\}. Indices 1 and 2 correspond to the x and y directions, respectively. The reason that ε212 = ε221 and d212 = d221 is because the strain tensor is usually defined to be symmetric, namely, εijk = εjik. The piezoelectric coefficients ε212 and d212 describe the response of polarization to shear strain ε22. In the following, we particularly focused on \{ε111, ε122\} and \{d111, d122\}, as well as the relationship between the εijk and dijk.

By definition, the tensors are related by

\[ ε_{ijk} = \frac{∂P_j}{∂σ_{ijk}}, \]

\[ d_{ijk} = \frac{∂P_j}{∂σ_{ijk}}. \]

where Cmnjk are elastic constants. In 2D structures, an index can be either 1 or 2. Therefore,

\[ e_{111} = d_{111}C_{1111} + d_{122}C_{2211}, \]

\[ e_{122} = d_{111}C_{1122} + d_{122}C_{2222}. \]

Using the Voigt notation, we simplify it as \[ e_{11} = e_{111}, \]
\[ e_{12} = e_{122}, d_{11} = d_{111}, d_{12} = d_{122}, C_{11} = C_{1111}, C_{12} = C_{1122} = C_{2211}. \]

Then, we calculated d11 and d12 by e11 and e12 as

\[ d_{11} = \frac{e_{11}C_{22} - e_{12}C_{12}}{C_{11}C_{22} - C_{12}^2}, \]

\[ d_{12} = \frac{e_{12}C_{11} - e_{11}C_{12}}{C_{11}C_{22} - C_{12}^2}. \]

We have directly calculated the polarization of the MX monolayers by applying the uniaxial strain ε11 and ε22 to the orthorhombic unit cell along the x and y directions, respectively. The change of polarization along the y direction is zero, because the mirror symmetry still remains under an uniaxial strain for the C2v point group. The values of e11 and e12 are evaluated by a linear fit of 2D unit-cell polarization change along the x direction (ΔPj) with respect to ε11 and ε22. In Figs. 2(a) and 2(b), we use ε11 and ε22 ranging from −0.005 to 0.005 in steps of 0.001 in the clamped-ion case and −0.01–0.01 in steps of 0.002 in the relax-ion case. The dense steps of 0.001 are required for monolayer SnSe and SnS because their linear polarization changes occurring in the strain region are very small, less than ±0.004, as shown in Figs. 2(c) and 2(d). For e11, the trend of polarization vs. strain is different for the cases of GeS and GeSe, and for e12, the trend is different for SnS and SnSe. This is because of the competition between ionic polarization contribution and electronic polarization for e11 of GeS and GeSe, and e12 of SnS and SnSe. The relaxed-ion (or clamped-ion) d11 and d12 coefficients are finally calculated by the corresponding e11, e12 coefficients and elastic stiffness coefficients C11, C22, and C12 based on Eqs. (8) and (9).

We have summarized the calculated e11, e12, d11, and d12 coefficients in Table III. The most useful piezoelectric coefficients (relaxed-ion d11 and d12), which reflect how much polarization charge can be generated with a fixed force

<table>
<thead>
<tr>
<th>Material</th>
<th>C11 (N/m)</th>
<th>C22 (N/m)</th>
<th>C12 (N/m)</th>
<th>ν⊥</th>
</tr>
</thead>
<tbody>
<tr>
<td>Clamp-ion</td>
<td></td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>GeS</td>
<td>48.50</td>
<td>58.19</td>
<td>32.92</td>
<td>0.22</td>
</tr>
<tr>
<td>GeSe</td>
<td>40.76</td>
<td>51.16</td>
<td>31.18</td>
<td>0.25</td>
</tr>
<tr>
<td>SnS</td>
<td>46.09</td>
<td>50.42</td>
<td>33.46</td>
<td>0.29</td>
</tr>
<tr>
<td>SnS</td>
<td>43.96</td>
<td>47.60</td>
<td>30.66</td>
<td>0.32</td>
</tr>
<tr>
<td>MoS2</td>
<td>150</td>
<td>153</td>
<td>48</td>
<td>0.34</td>
</tr>
<tr>
<td>GaSe</td>
<td>108</td>
<td>108</td>
<td>32</td>
<td>0.39</td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th>Relax-ion</th>
<th></th>
<th></th>
<th></th>
<th></th>
</tr>
</thead>
<tbody>
<tr>
<td>GeS</td>
<td>80.30</td>
<td>85.00</td>
<td>42.07</td>
<td>0.35</td>
</tr>
<tr>
<td>GeSe</td>
<td>74.50</td>
<td>78.16</td>
<td>40.18</td>
<td>0.38</td>
</tr>
<tr>
<td>SnS</td>
<td>71.00</td>
<td>75.42</td>
<td>37.54</td>
<td>0.41</td>
</tr>
<tr>
<td>SnS</td>
<td>68.96</td>
<td>70.16</td>
<td>34.66</td>
<td>0.42</td>
</tr>
<tr>
<td>MoS2</td>
<td>140</td>
<td>150</td>
<td>60</td>
<td>0.44</td>
</tr>
<tr>
<td>GaSe</td>
<td>98</td>
<td>102</td>
<td>32</td>
<td>0.45</td>
</tr>
</tbody>
</table>

TABLE II. DFT-PBE calculated in-plane elastic stiffness C11, C22, and C12 of monolayer group IV monochalcogenides. The Poisson ratio ν⊥ is calculated for the relaxed ion case. The data of a typical TCMD monolayer material, MoS2, and a typical group III monochalcogenide, GaSe, are listed for reference as well.
and thus decide the mechanic-electrical energy converting ratio, are about 75–250 pm/V. Compared with those of frequently used bulk piezoelectric materials, such as $a$-quartz, wurtzite AlN, and ZnO,7,14,52–54 and recently emerging 2D piezoelectric materials, such as MoS2 and GaSe,14,16,23 these values are about two orders of magnitude larger, as shown in Fig. 3.

Finally, we find that the relaxed-ion $d_{11}$ and $d_{12}$ coefficients in the MX monolayers obey a periodic trend, as shown in the inset of Fig. 3. GeS possesses the smallest piezoelectric effect ($d_{11} = 75.43$ pm/V and $d_{12} = 50.42$ pm/V), and moving upward in groups 14 (crystallogens) and 16 (chalcogenide) enhances the magnitude of the effect until SnSe, which has the largest coefficient ($d_{11} = 250.58$ pm/V, $d_{12} = -80.31$ pm/V), is reached. Interestingly, this trend is similar to that discovered in the hexagonal TMDCs.14 More calculations on similar puckered $C_{2v}$ symmetry materials may be necessary to conclude the interesting trend of piezoelectric effects revealed in those honeycomb structures.18

These group IV monochalcogenides have highly desirable properties useful for a broad range of applications. On the other hand, for realistic devices, many other factors, in addition to the piezoelectric coefficients, will need to be considered. For instance, substrate effects and carrier mobilities are important for deciding the converting ratio in energy capture devices and the mechanical fatigue of these flexible materials has not been tested yet. It is also known that the layer number may dramatically impact the piezoelectric effect.22 These are beyond the scope of this letter, but further research is expected.

By reliable simulations, we have demonstrated that monolayer group IV monochalcogenides MX, GeS, GeSe, SnS, and SnSe are strongly piezoelectric. Their piezoelectric coefficients are surprisingly one to two orders of magnitude larger than other frequently used piezoelectric materials. Encouraged by experimental achievements of monolayer samples, we expect that the huge piezoelectric properties of these materials to provide new platforms for electronic and piezotronic devices, and enable previously inaccessible avenues for sensing and control at the nanoscale.

![Clamped-Ion and Relaxed-Ion](image)

FIG. 2. Change of unit-cell polarization per area of the MX monolayers along the x direction after applying uniaxial strain $e_{11}$ (a) and (c) and $e_{22}$ (b) and (d). The piezoelectric coefficients $e_{11}$ and $e_{12}$ correspond to the slope of lines obtained through linear fitting of polarization change with respect to $e_{11}$ and $e_{22}$.

![Fig. 3](image)

FIG. 3. Comparison of the characteristic piezoelectric coefficient ($d_{11}$) between previously known piezoelectric materials and our proposed group IV monochalcogenides. A break in the y-axis is necessary to make previously studied materials visible. The inset shows the trends of relaxed-ion structural, elastic, and piezoelectric properties.

<table>
<thead>
<tr>
<th>Material</th>
<th>$e_{11}$ ($10^{-10}$ C/m)</th>
<th>$e_{12}$ ($10^{-10}$ C/m)</th>
<th>$d_{11}$ (pm/V)</th>
<th>$d_{12}$ (pm/V)</th>
</tr>
</thead>
<tbody>
<tr>
<td>GeS</td>
<td>1.62</td>
<td>-11.6</td>
<td>16.39</td>
<td>29.21</td>
</tr>
<tr>
<td>GeSe</td>
<td>0.62</td>
<td>-11.0</td>
<td>20.75</td>
<td>31.11</td>
</tr>
<tr>
<td>SnS</td>
<td>0.36</td>
<td>-7.9</td>
<td>22.07</td>
<td>29.12</td>
</tr>
<tr>
<td>SnSe</td>
<td>0.65</td>
<td>-6.68</td>
<td>20.46</td>
<td>27.21</td>
</tr>
<tr>
<td>Bulk $a$-quartz</td>
<td></td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>Bulk AlN (wurtzite)</td>
<td></td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>ZnO</td>
<td>0.89 ($e_{33}$)7 theory</td>
<td>-0.51 ($e_{31}$)7 theory</td>
<td>9.93 ($d_{33}$)52 exp.</td>
<td></td>
</tr>
<tr>
<td>MoS2</td>
<td>3.6414 theory</td>
<td>3.7314 theory</td>
<td></td>
<td></td>
</tr>
<tr>
<td>GaSe</td>
<td>5.2216 theory</td>
<td>9.6716 theory</td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

TABLE III. Calculated clamped-ion and relaxed-ion piezoelectric coefficients, $e_{11}$, $e_{12}$, $d_{11}$, and $d_{12}$.

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42See supplementary material at http://dx.doi.org/10.1063/1.4934750 for band structure of intrinsic GeS, GeSe, SnS, and SnSe.


